



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT: COPPOLA, Giuseppe

SERIAL NO.: 10/624,189

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EXAMINER: Lyons, M.A.

TITLE: INTERFEROMETRIC SYSTEM FOR THE SIMULTANEOUS MEASUREMENT OF THE INDEX OF REFRACTION AND OF THE THICKNESS OF TRANSPARENT MATERIALS, AND RELATED PROCEDURE

CERTIFICATE OF MAILING UNDER 37 CFR 1.8(a)

Commissioner for Patents  
Portion. O. Box 1450  
Alexandria, VA 22313-1450

Sir:

I hereby certify that the attached correspondence comprising:

AMENDMENT "A"

is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to:

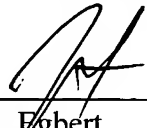
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on 12-21-05

Date

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Respectfully submitted,

  
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